

# Fan Yang

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## EDUCATION

**Aug 2012 to May 2014    University of Southern California, Los Angeles**

- Master of Science, Electrical Engineering
- Main Coursework: MOS VLSI Design, VLSI System Design, Solid State Processing and Integrated Circuits Laboratory, Computer Systems Organization, Computer Systems Architecture, Diagnosis and Design of Reliable Digital Systems, Analysis of Algorithms

**Sep 2008 to Jun 2012    Henan University of Technology, China**

- Bachelor of Engineering, Electrical Engineering and Automation

## SKILLS

**Language:** Verilog, System Verilog, Perl, Python, C/C++

**Tools:** Modelsim, Cadence Virtuoso, Cadence NCSim, NCVerilog, Synopsys DC, TetraMax, Xilinx ISE13.2, FPGA, Cadence SOC Encounter, Synopsys PrimeTime, Protel

## PROJECT EXPERIENCE

- **ASIC Verification using System Verilog (System Verilog)    Dec 2013**  
Verifying simple DUT with constraint random coverage and different assertions (immediate and concurrent). Implement a simple FSM by using more Object Oriented Programming including classes and objects. Extending class has been added to override the original function.
- **DDR2 SDRAM Memory Controller Design (Verilog, Cadence Encounter)    Oct 2013 to Nov 2013**  
Implement a 512Mb DDR2 SDRAM controller in Verilog HDL and simulate the design with Denali's DDR2 model using Cadence NC-Verilog. Automatic place and route has been performed by Cadence Encounter after synthesizing. Timing analysis and debugging have also been implemented.
- **Diagnosis and test system for Combinational Circuit (C Programming)    Nov 2013 to Dec 2013**  
Design and implement a testing program for the combinational circuit with two ATPG algorithms: D-algorithm and PODEM, two fault simulators: parallel and deductive, and one preprocessor. The program is based on C programming and realizes the functions such as: test vectors creativity and their corresponding outputs as well as fault location.
- **Classical General Purpose Microprocessor Design (Virtuoso, Perl)    May 2013**  
Implement a 16bit multi-cycle microprocessor in gate level. Instruction fetch and decode is done by a control signal vector file via Perl-scripting. A 1024-bit 6T SRAM has been designed as main memory. My design uses dynamic logic circuit with domino structure. And releases power\*delay\*area optimization with clock gating.
- **DFT , BIST Realization and Fault Table Generation (NCVerilog, TetraMax)    Oct 2013**  
Synthesizing the RTL to include scan cells. Then use TetraMax ATPG automatically generates high quality manufacturing test patterns for SA-faults. For BIST, the design has two modes: normal and test with LFSR counter.
- **Simulation-based Verification using Python Scripting (Python)    Oct 2013**  
Implement a python scripting in order to automate the simulation process, perform result checking and generate a testing report automatically.
- **FPGA Prototyping and Code Coverage lab (Verilog, Xilinx)    Nov 2013**  
Debugging the FPGA design with given constraints. Rising the code coverage to 100% with Modelsim. Optimization the design to meet the timing and power constraints. Implement the Viterbi Decoder with Viterbi algorithm, using the FPGA simulator to verify the functionality.
- **Single-Clock and Double-Clock FIFO Design(Verilog)    Sep 2013**  
Design and implement a circular single-clock FIFO in 4-value system by using three methods: fill-counter, almost full/almost empty and (n+1) bit pointer. For double-clock FIFO design, double synchronization and gray code have been used to solve the metastability and racing problem. The designs with min clock have been synthesized via Synopsys DC.
- **TCAM Design (Verilog)    Oct 2013**  
Design a general-purpose ternary content-addressable memory (TCAM) with 3-value system. A LRU is used to keep the history of each memory location and determines the victim when the memory is full. The design has the min-clock period.
- **JTAG (Verilog)    Nov 2013**  
Implement an on-chip JTAG interface to test a design, and familiar with the IEEE testing standard 1149.1(JTAG).